

**Search Notes**

Application/Control No.

10/699,542

Examiner

Peter Coughlan

Applicant(s)/Patent under  
Reexamination

LI ET AL.

Art Unit

2129

**SEARCHED**

Class	Subclass	Date	Examiner
706	45	8/31/2006	PDC
702	7	8/31/2006	PDC
707	102	8/31/2006	PDC
701	50	8/31/2006	PDC
705	7	8/31/2006	PDC
702	22	8/31/2006	PDC
424	122	8/31/2006	PDC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East--false positive, false negative, false identification rates, tester, operating characteristics, processed data	8/31/2006	PDC
East--II--characteristic curves, alternatives, classifier, cross validation, minimum, minimal, taxonomy, model, weight	8/31/2006	PDC
East--III--sample data, factorial analysis, one way layout	8/31/2006	PDC
IEEE--Jonathan Qiang Li, Lee A. Barford, one way layout, weight, processed data, factorial analysis, model	8/31/2006	PDC
IEEE--II--operating characteristics, sample data, minimum, minimal, tester, cross validation, identification rates, classifier	8/31/2006	PDC
IEEE--III--alternatives, characteristic curve, false positive, false negative	8/31/2006	PDC
Inventors Jonathan Qiang Li Lee A. Barford	8/31/2006	PDC
702/22 with fitting w/model, training set, math expression, weight,	8/31/2006	PDC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner